

Search Notes

Application/Control No.

10/765,565

Examiner

Chuck Huynh

Applicant(s)/Patent under
Reexamination

LEE ET AL.

Art Unit

2683

SEARCHED

Class	Subclass	Date	Examiner
455	414.1	2/3/2006	CH
455	3.01	2/3/2006	CH
455	412	2/3/2006	CH
379	93.35	2/3/2006	CH
379	88.13	2/3/2006	CH
455	435	2/3/2006	CH

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Talked to Steve D'agosta about 112	2/3/2006	CH
Class/Subclass/Combined Text	2/3/2006	CH
Citations/backward and forward/IDS	2/3/2006	CH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner